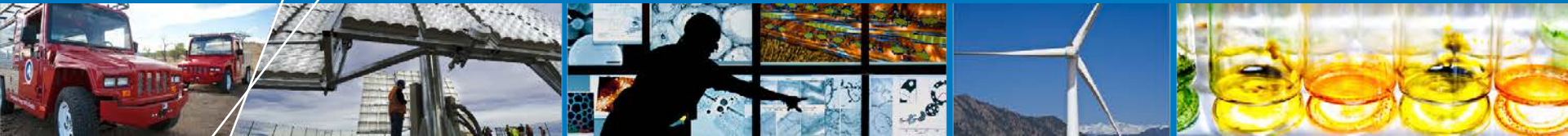


Performance and Reliability of Interface Materials for Automotive Power Electronics



Sreekant Narumanchi
National Renewable Energy Laboratory
sreekant.narumanchi@nrel.gov
(303) 275-4062

NREL Team members: Doug DeVoto, Mark Mihalic, Paul Paret

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*This presentation does not contain any
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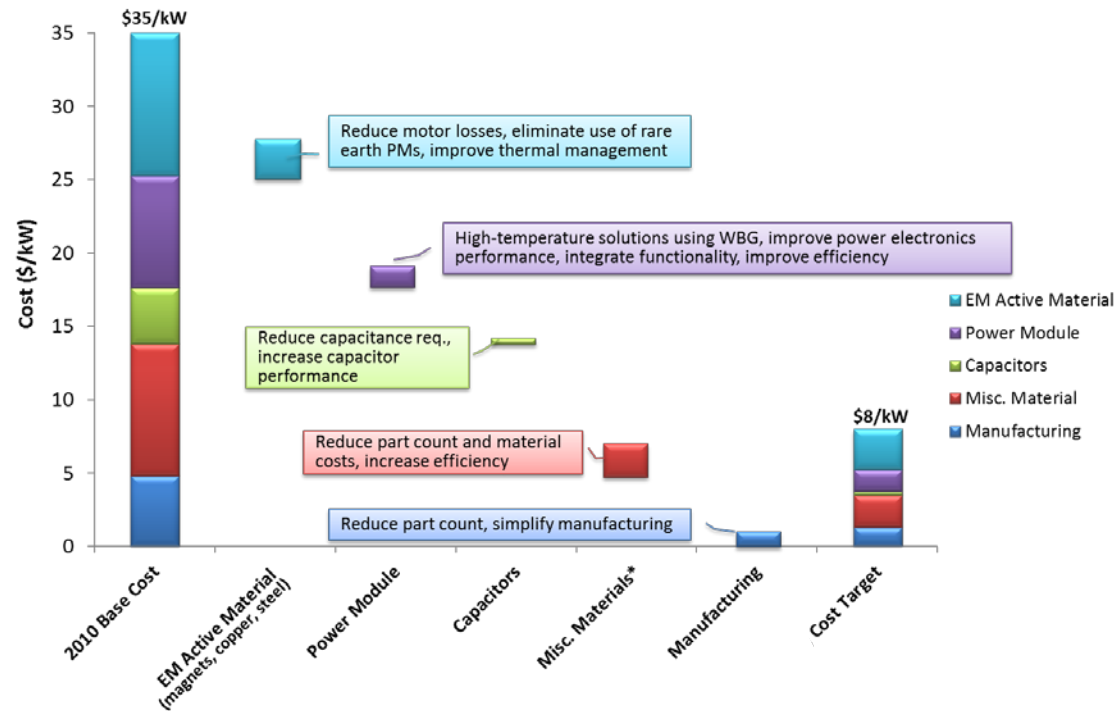


Outline

- Background
- State-of-the-art of interface materials/interfaces
- Non-bonded thermal interface materials (TIMs)
 - Thermal resistance
- Bonded interface materials (BIMs)
 - Thermal resistance
- Reliability of bonded interfaces (accelerated testing)
- Modeling of BIMs
- Summary

Importance of Thermal Management and Reliability

- Excessive temperature degrades the performance, life, and reliability of power electronics and electric motors.
- Advanced thermal management technologies enable
 - keeping temperature within limits
 - higher power densities
 - lower cost materials, configurations and system.
- Improve lifetime/reliability as well as develop new predictive lifetime models.



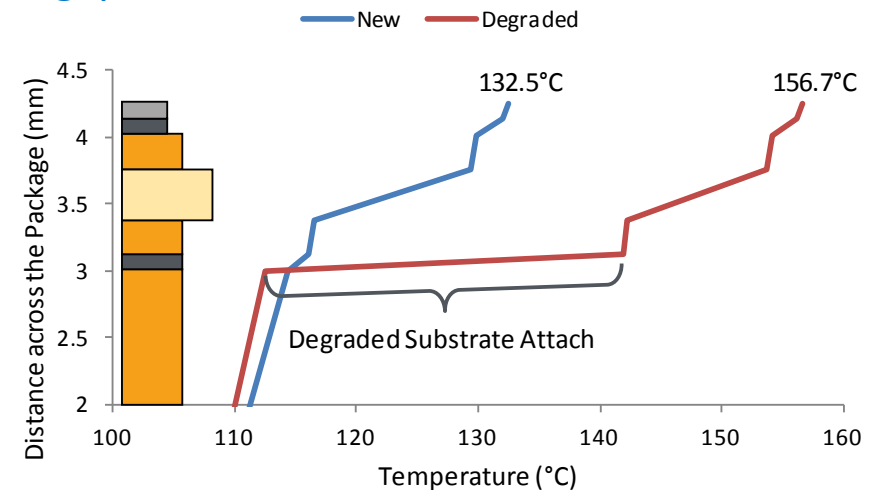
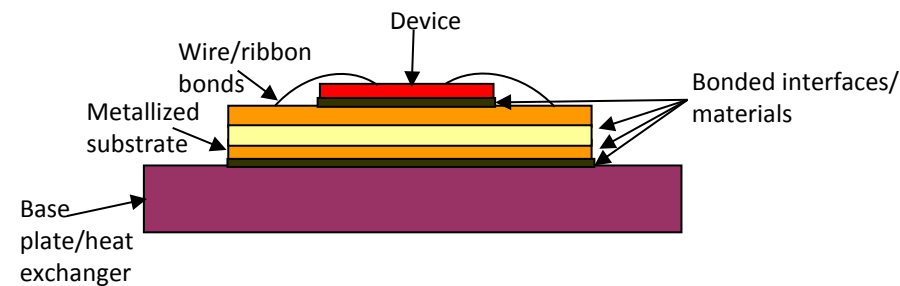
* Inverter: cold plate, drive boards, thermal interface material, bus bar, current sensors, housing, control board, etc.
Motor: bearings, housing, sensors, wire varnish and insulation, potting materials, shaft, etc.

Courtesy: Oak Ridge National Laboratory (ORNL)

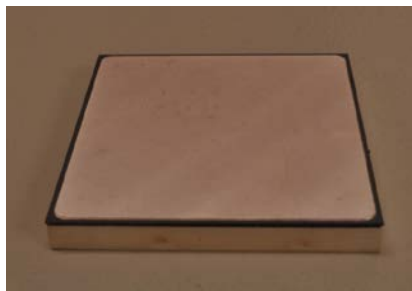
Reduce cost, improve reliability

State-of-the-Art of Interfaces/Interface Materials

- Interfaces (especially polymeric interface materials) can pose a major bottleneck to heat removal.
- BIMs, such as solder, degrade at higher temperatures and are prone to thermomechanical failure.
- Need for improved reliability as well as predictive lifetime design tools for lowering cost.
- Important for configurations employing wide bandgap devices.



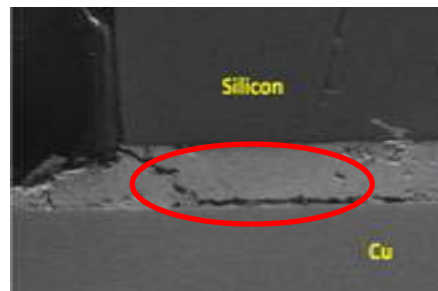
Bonded Interface



Voiding



Cracking

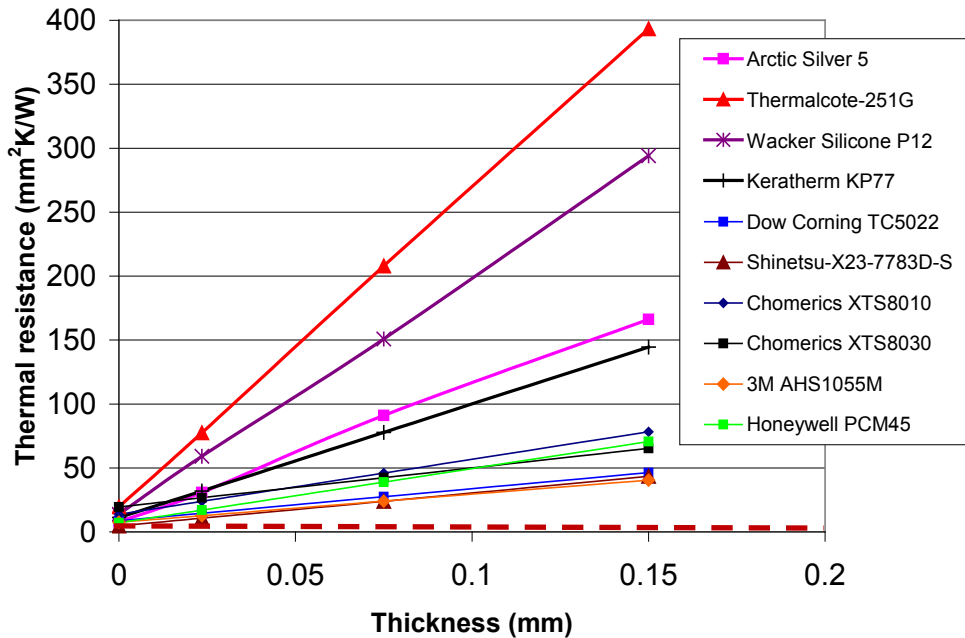


Delamination

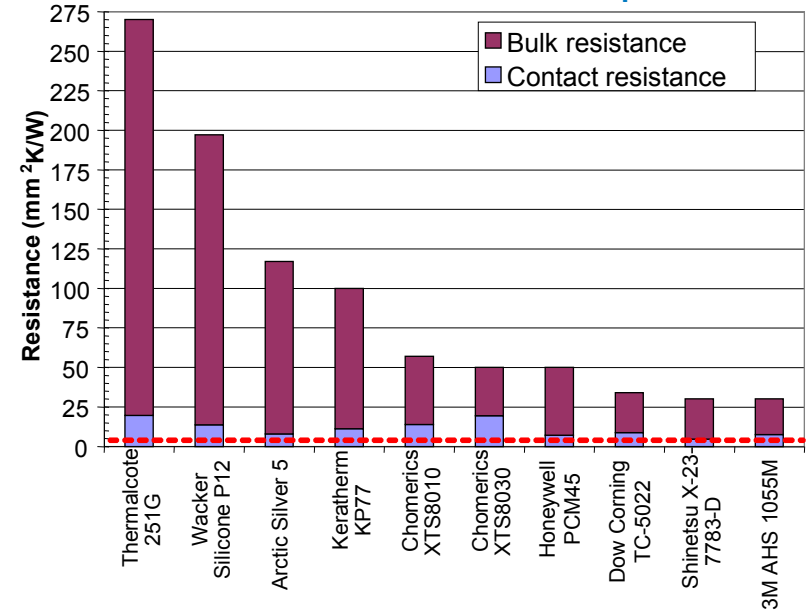


Thermal resistance of various non-bonded TIMs

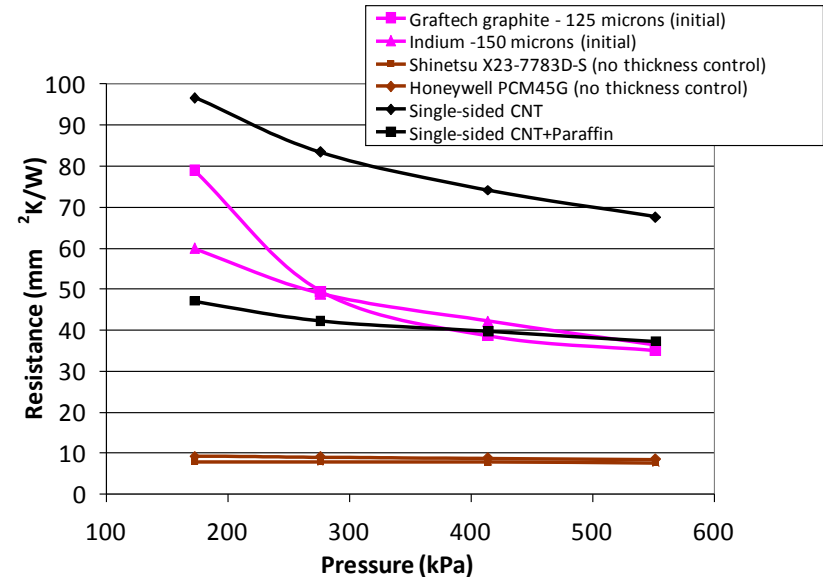
172 kPa, ~ 75 C sample temperature



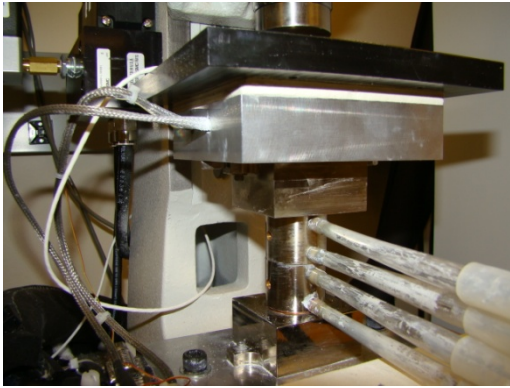
TIM thickness in all cases is 100 μm



- Red dashed line in the two figures above is the target thermal resistance (**3 to 5 mm²K/W**).
- Most non-bonded TIMs do not come close to meeting thermal specification of 3 to 5 mm²K/W at approximately **100-μm** bond line thickness.



Thermal Resistance of Sintered Silver and Solder



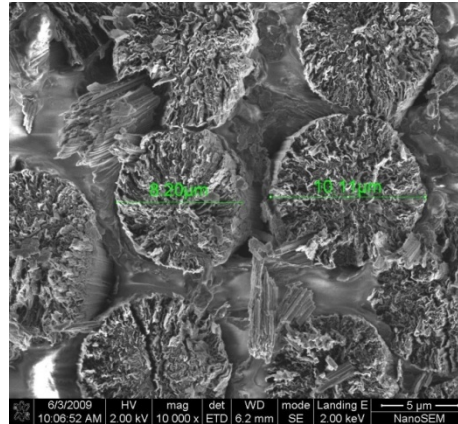
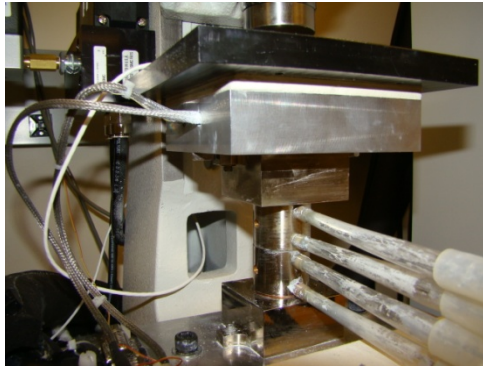
ASTM test fixture

Samples	Thickness (μm)	Resistance ($\text{mm}^2\text{K/W}$)
Silvered Cu-Cu sintered interface	20	5.8
	27	8.0
	64	5.4
Cu-Cu soldered interface (SN100C)	80	1.0
	150	4.8
	200	3.7

- The thermal resistance tests were performed using the NREL ASTM TIM apparatus
 - Average sample temperature $\sim 65^\circ\text{C}$, pressure is 276 kPa (40 psi).
- The silvered Cu-Cu sintered interface showed promising thermal performance.
- Results hinted at some problems with the bonding of the silvered Al-Al interface.
- The initial thermal results for a lead-free solder (SN100C) interface were promising.
- Bonded interface resistance in the range of 1 to 5 $\text{mm}^2\text{K/W}$ is possible.

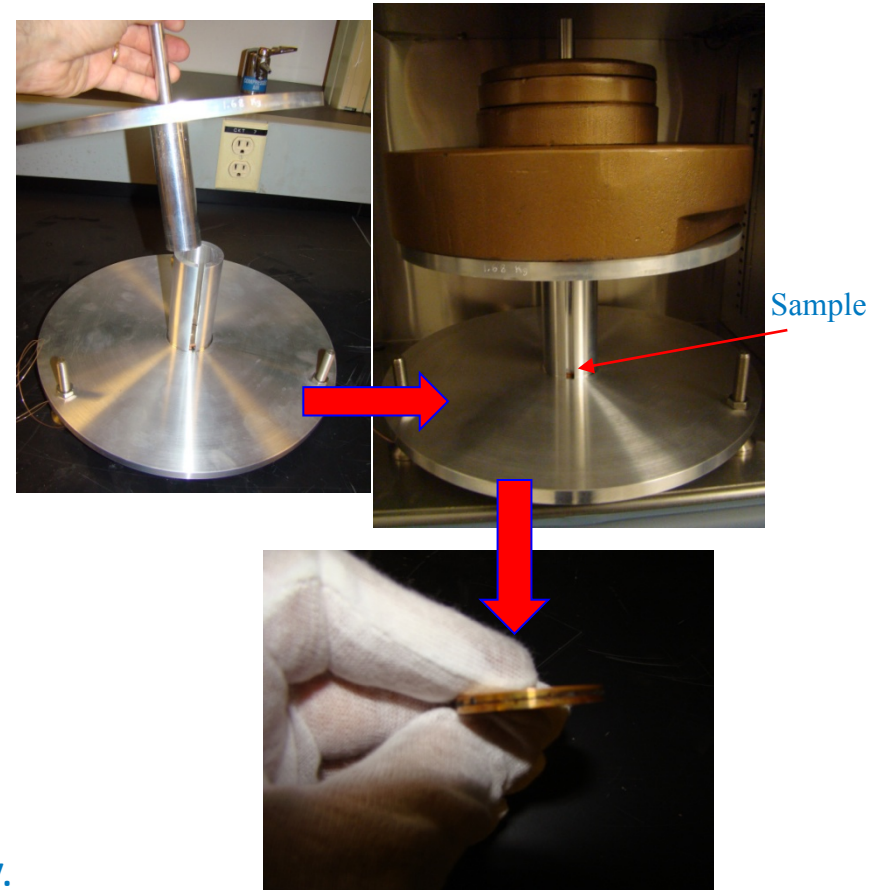
Thermal Resistance of Thermoplastics with Embedded Fibers

Thermoplastics with embedded carbon fibers



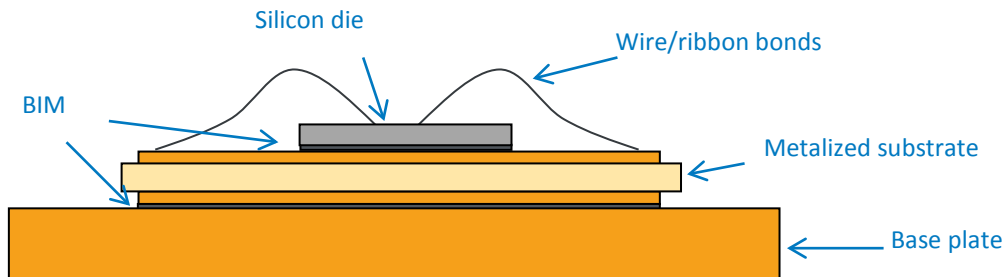
- Thermoplastic films (provided by Btech) bonded between 31.8-mm-diameter copper disks.
- Promising thermal results (**8 mm²K/W for 100-µm bondline thickness**).
- Continuing work at NREL to further decrease contact resistance to approach target thermal performance, as well as characterize reliability.

Sequence of bonding steps

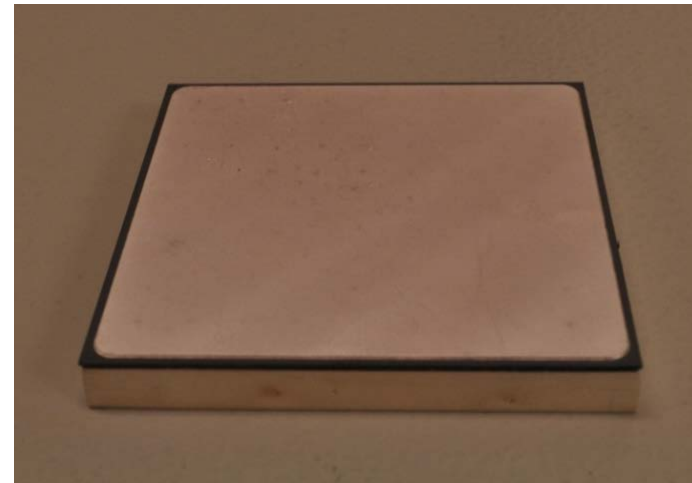


Reliability of Bonded Interfaces

- Investigate the reliability of emerging BIMs to meet the thermal performance target of 3 to 5 mm²K/W.
- Identify failure modes in emerging BIMs.
- Experimentally characterize their life under known conditions.
- Develop lifetime estimation models.

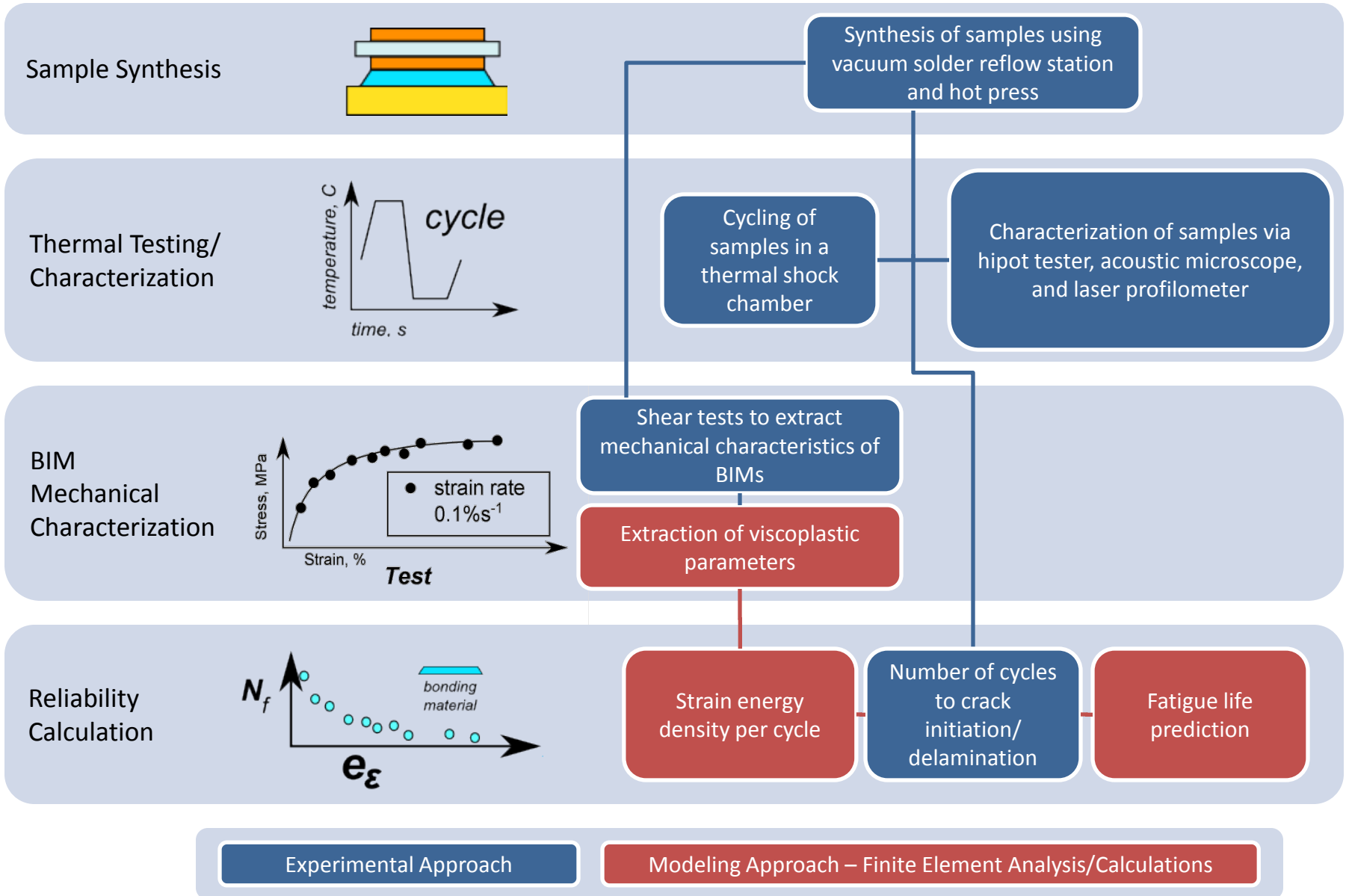


Traditional Power Electronics Package



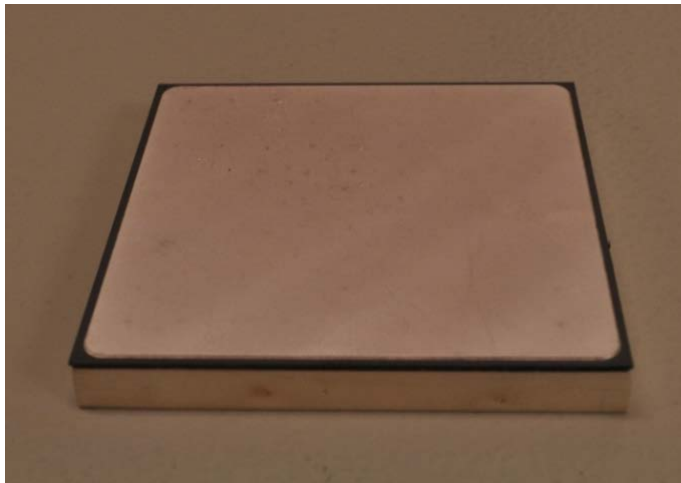
Sample Assembly

Approach



Approach – Sample Assembly

- Five samples of each BIM were synthesized for testing and included:
 - Silver plating on the substrate and base plate.
 - Substrate based on a Si_3N_4 active metal bonding process; base plate material is copper.
 - An interface between substrate and base plate with 50.8-mm x 50.8-mm footprint.
- Samples followed manufacturer-specified reflow profiles, and bonds were inspected for quality.

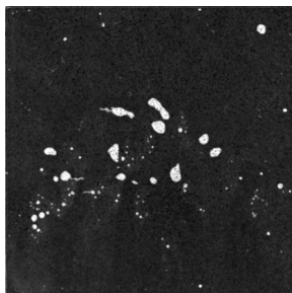
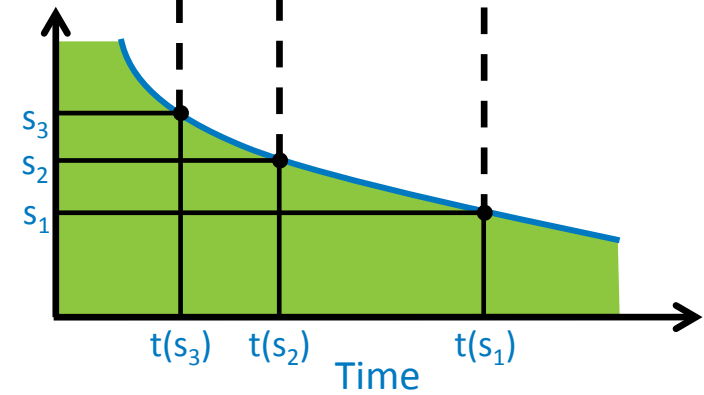
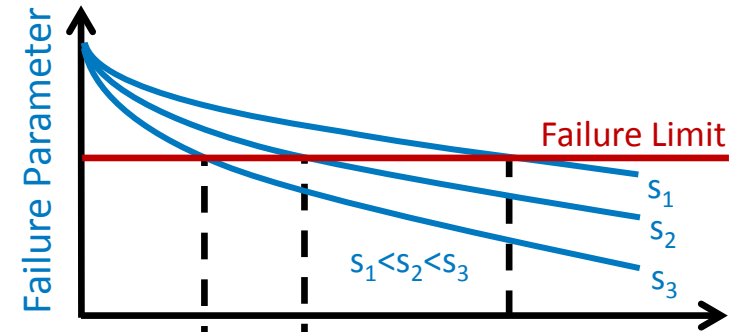


Sample Assembly

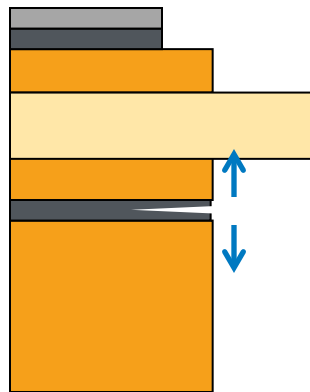
Bond Material Type	Name	Comments
Solder	Kester Sn63Pb37	Baseline (lead-based solder)
Sintered Silver	Semikron	Based on Semikron synthesis process
Adhesive	Btech HM-2	Thermoplastic (polyamide) film with embedded carbon fibers

Approach – Temperature Cycling

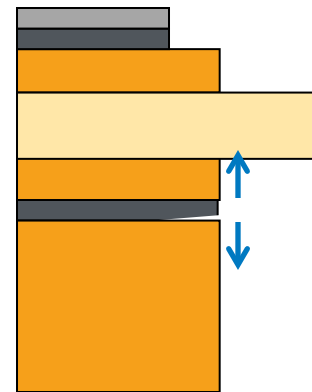
- Cycle Profile
 - -40°C to 150°C
 - 5°C/minute ramp rate
 - 10 minute dwell/soak time
- Failure Mechanisms
 - BIM: voids and cohesive or adhesive/interfacial fractures
 - Substrate: Cu-to-Si₃N₄ delamination and Si₃N₄ cracking



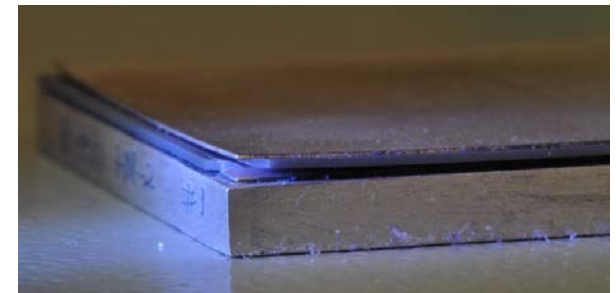
Voids



Cohesive Fracture



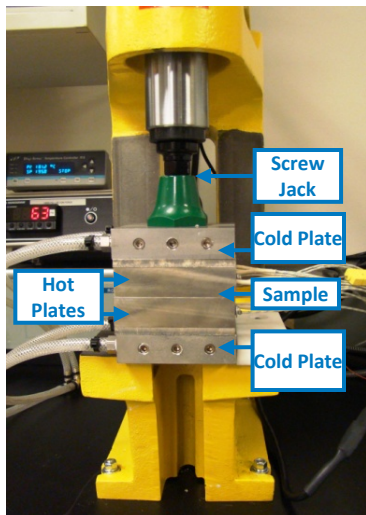
Adhesive/Interfacial Fracture



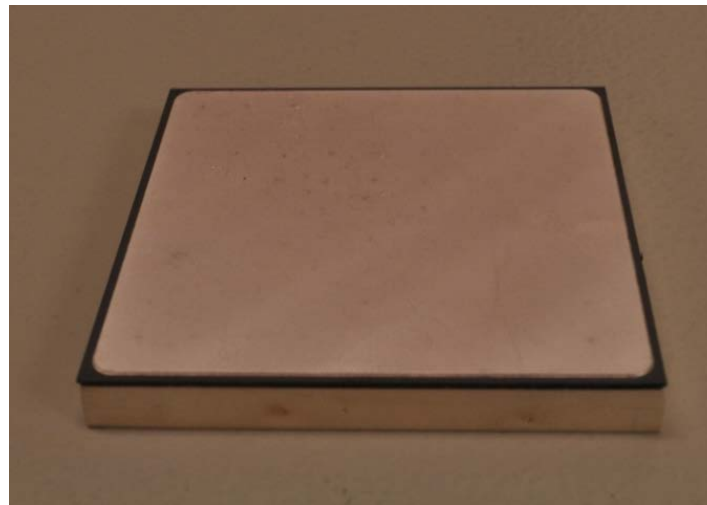
Substrate Delamination and Cracking

Reliability of Thermoplastic-based BIM

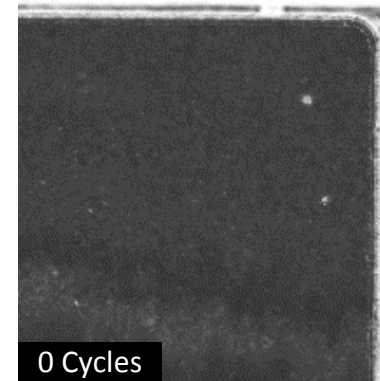
- Btech HM-2 (Carbon fibers within polyamide matrix)
 - Bonding
 - HM-2 was cut to the base plate dimensions
 - The sample assembly was placed in the hot press and raised to 195°C
 - 1 MPa (150 psi) of pressure was applied
 - Reliability Results
 - After 2,000 cycles, the bonded interface remained defect-free



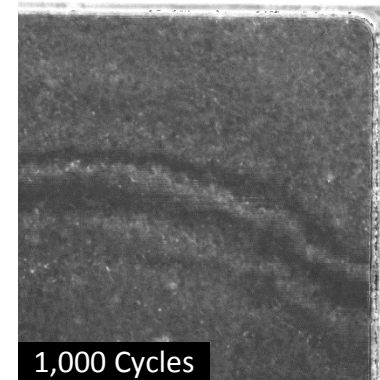
Hot Press



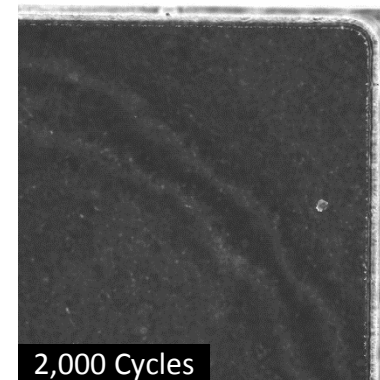
Sample Assembly



0 Cycles



1,000 Cycles



2,000 Cycles

Reliability of Sintered Silver-based BIM

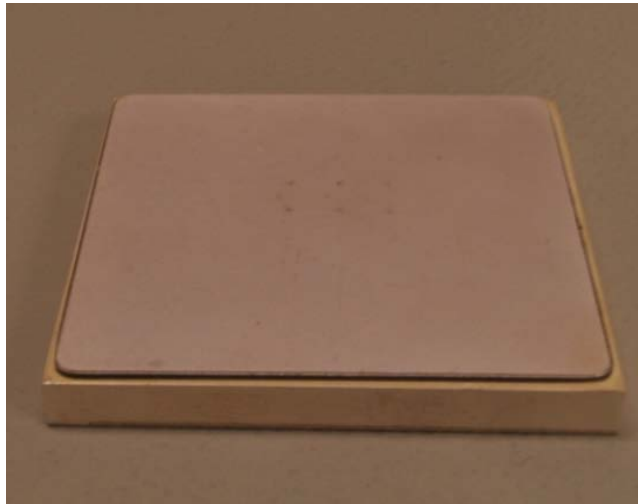
- Semikron Sintered Silver

- Bonding

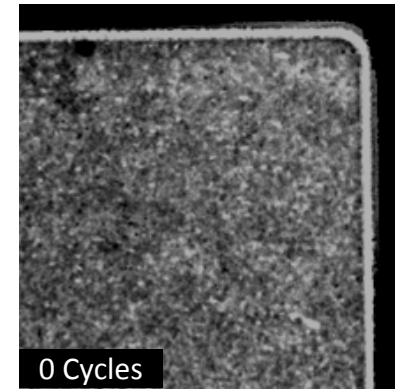
- Si_3N_4 edges were ground off to match the metallization layer.
 - The sample assembly was placed in a hot press and raised to its processing temperature, then pressure was applied.
 - Compression testing of substrates at ORNL showed cracking of substrates required between 30 MPa to 50 MPa of pressure.

- Reliability Results

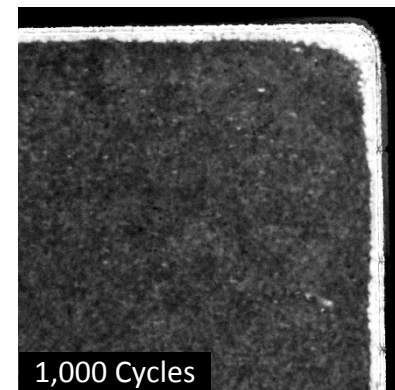
- Uniform bonds were obtained.
 - Adhesive fracture has initiated at the bonding perimeter.



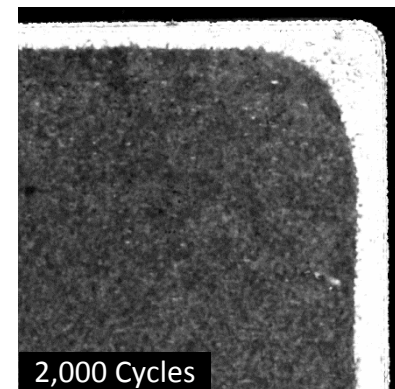
Sample Assembly



0 Cycles



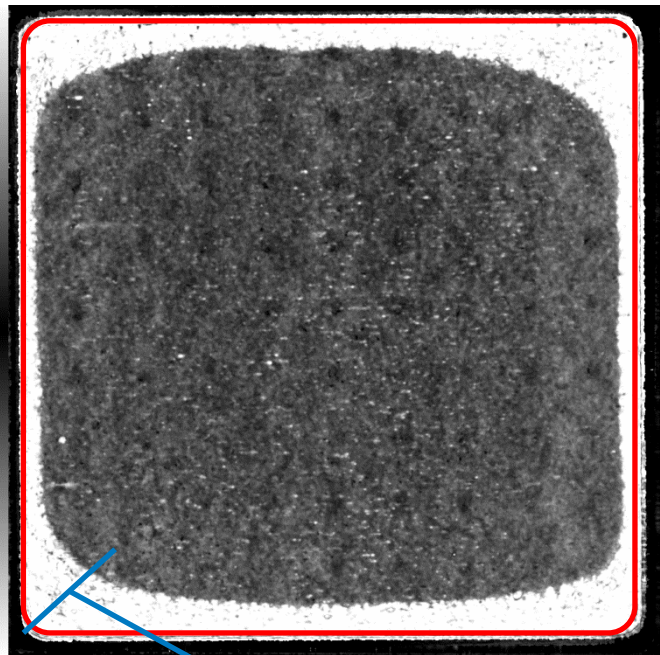
1,000 Cycles



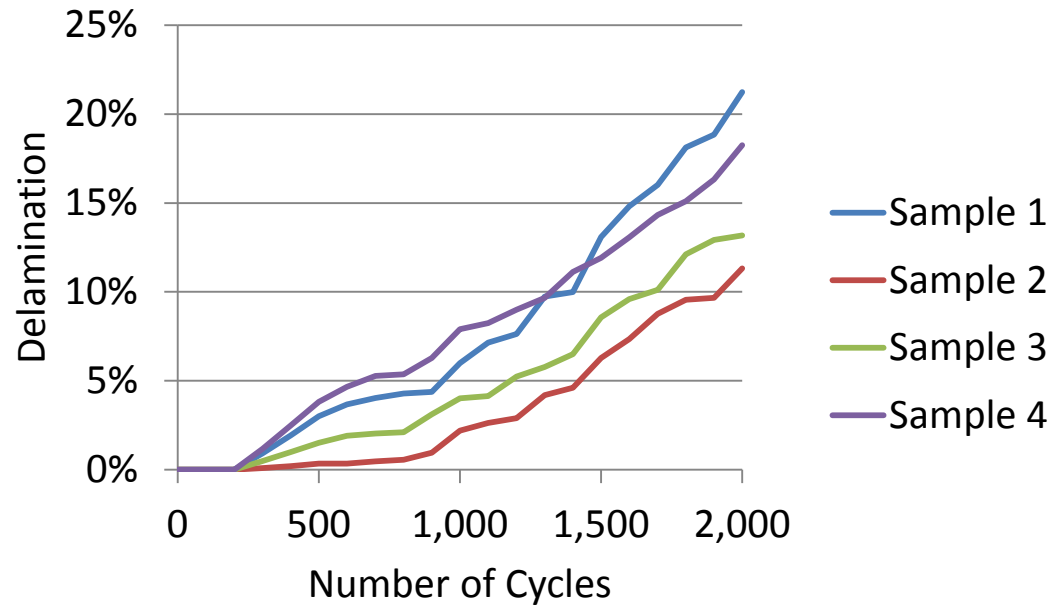
2,000 Cycles

Reliability of Sintered Silver-based BIM

- After 2,000 cycles, perimeter fracturing has reached 11% to 21%.

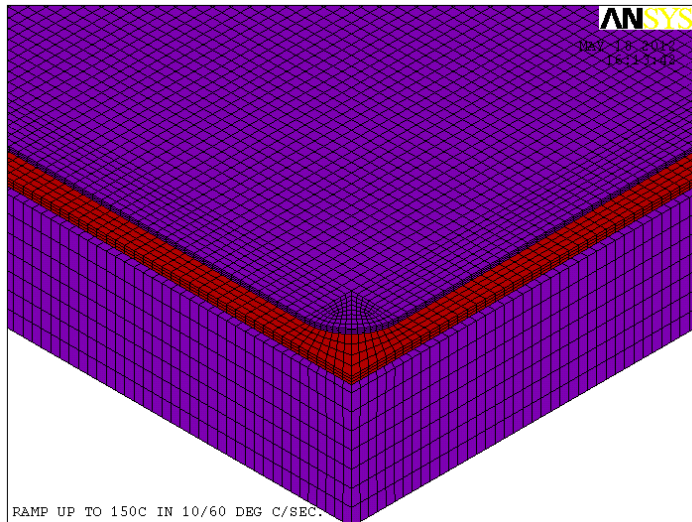


2,000 Cycles

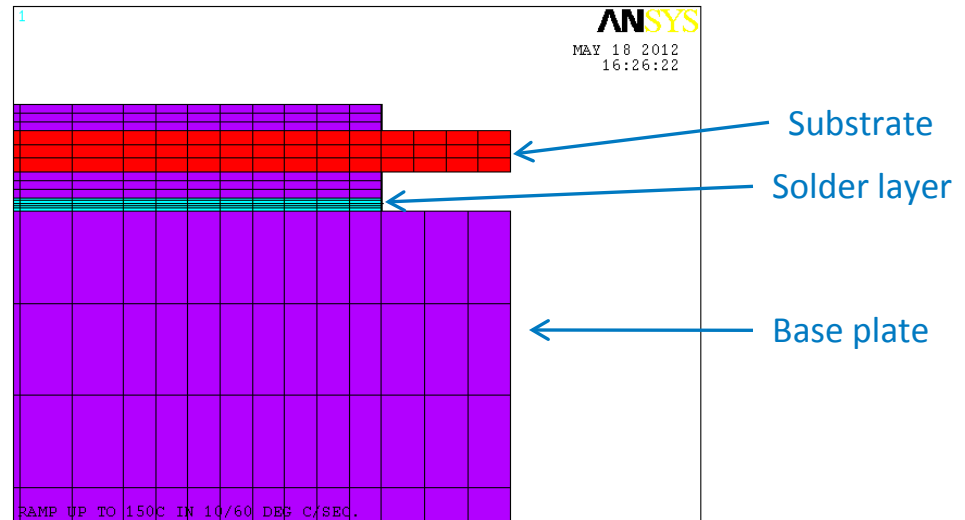


Credit: Paul Paret

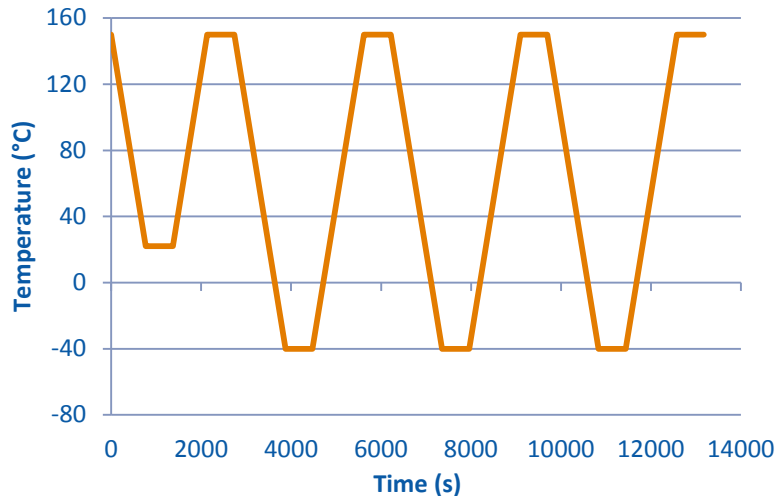
BIM Finite Element Modeling (FEM)



Quarter Symmetry Model

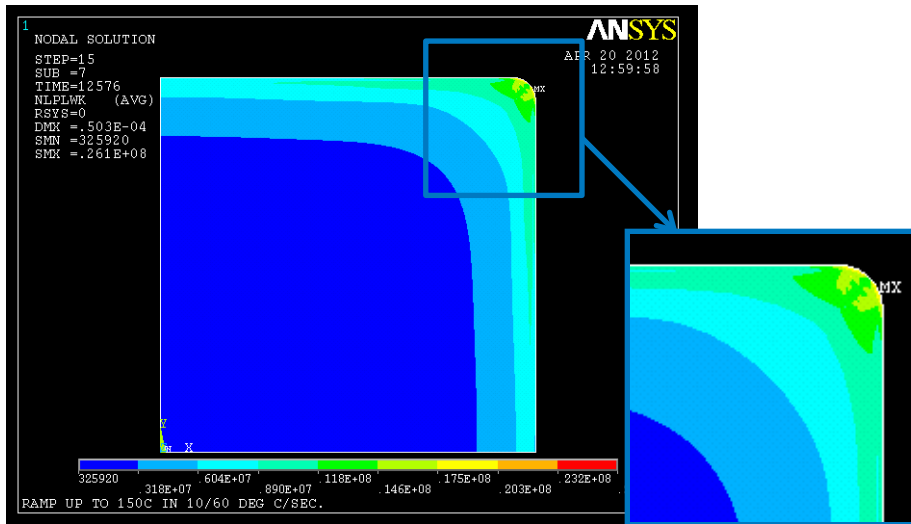


Temperature Cycling Profile

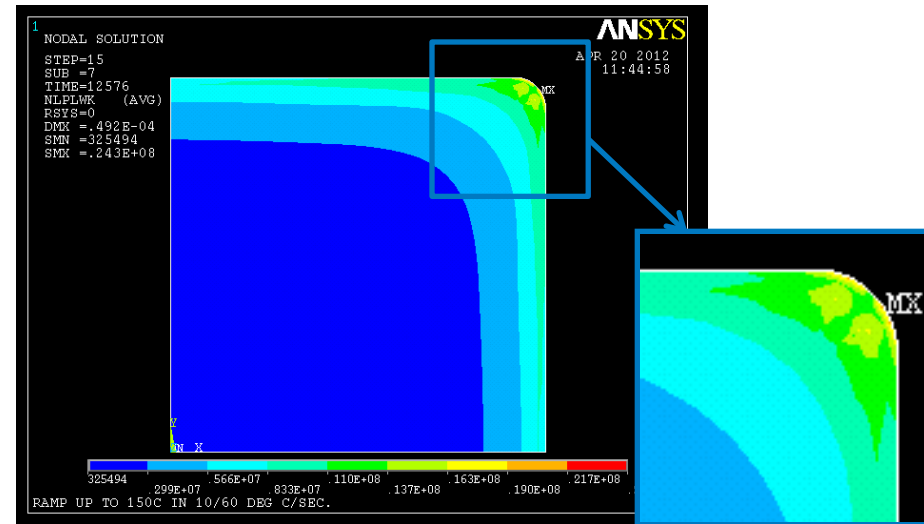


- Temperature cycling parameters:
 - -40°C to 150°C
 - 5°C/minute ramp rate
 - 10 minute dwell/soak time
- Viscoplastic material model applied to solder layer
- Temperature-dependent elastic material properties incorporated for base plate and substrate

BIM FEM

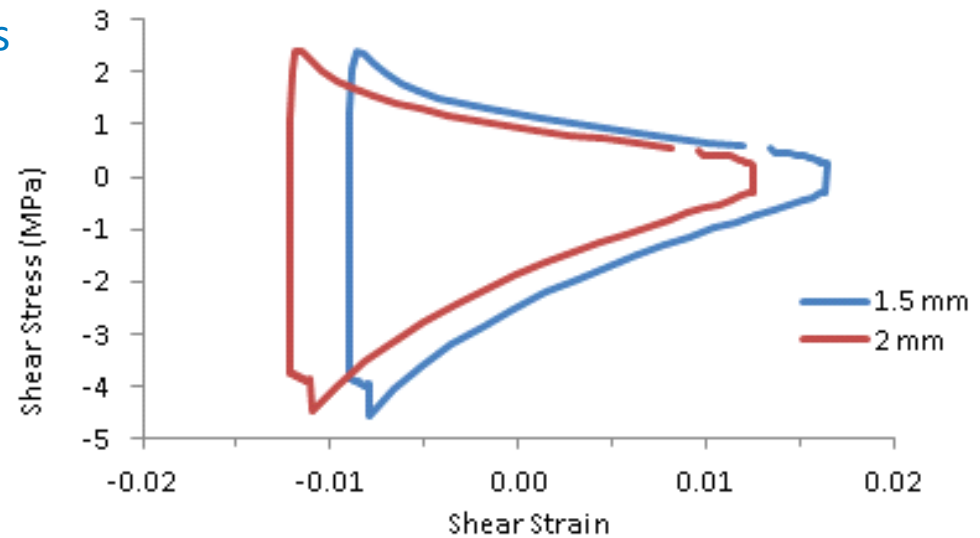
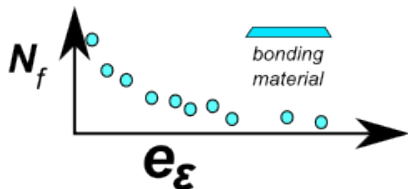


Solder Layer Top Surface (1.5-mm radius)



Solder Layer Top Surface (2-mm radius)

- Strain energy density in the bonded joint region shown to decrease as fillet radius increases (11.3 MPa and 11.2 MPa for 1.5 mm and 2 mm, respectively).
- Strain energy density versus cycles-to-failure correlation to be obtained for lead-based and lead-free solders.



Summary

- TIMs/BIMs are a key enabling technology for compact, light-weight, low-cost, reliable packaging and for high-temperature coolant and air-cooling technical pathways.
- Characterization of thermal performance of TIMs/BIMs
 - 3 to 5 mm²K/W resistance at 100 μm is a difficult target for non-bonded TIMs
 - BIMs can meet this thermal target immediately after bonding – main question is reliability
- Characterization of reliability of BIMs
 - Synthesis of various joints between substrates and base plate, thermal shock/temperature cycling, high-potential test and joint inspection (C-SAM), and strain energy density versus cycles-to-failure models
 - Thermoplastic BIM is very reliable after 2,000 cycles, sintered silver BIM showing some significant edge delamination
- Initiated FEM for solder-bonded interface geometries – ultimate goal is to develop predictive lifetime model for BIM.

Summary

- **Current/Future Work**

- Complete 2,000 thermal cycles on all selected materials using Si_3N_4 -based substrates
- Report on reliability of each BIM under specified accelerated test conditions
- Derive viscoplastic parameters for lead-based and lead-free solders from double-lap shear test experiments
- Develop strain energy density versus cycles-to-failure predictive lifetime model for lead-based solder
- Expand strain energy density versus cycles-to-failure predictive lifetime model to lead-free solders
- Improve process for large-area sintered silver-based interface, and eventually develop predictive lifetime model

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For more information contact:

Principal Investigator
Douglas DeVoto
Douglas.DeVoto@nrel.gov
Phone: (303) 275-4256

APEEM Task Leader

Sreekant Narumanchi
Sreekant.Narumanchi@nrel.gov
Phone: (303) 275-4062